Memory FeRAM

2M (256 K \times 8) Bit SPI

MB85RS2MLY(AEC-Q100 Compliant)

DESCRIPTION

MB85RS2MLY is a FeRAM (Ferroelectric Random Access Memory) chip in a configuration of 262,144 words \times 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells. This product is specifically targeted for high-temperature environment such as automotive applications.

MB85RS2MLY adopts the Serial Peripheral Interface (SPI).

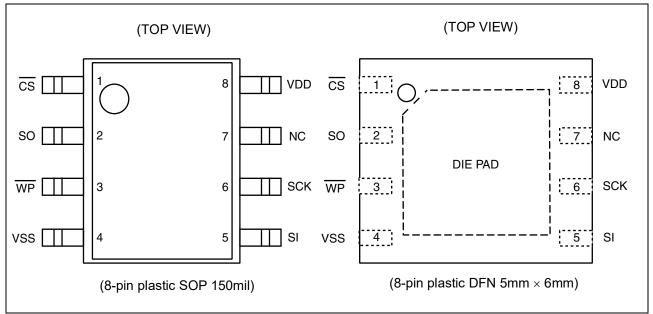
The MB85RS2MLY is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS2MLY can be used for 10¹³ read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E²PROM. As MB85RS2MLY does not need any waiting time in writing process, the write cycle time of MB85RS2MLY is much shorter than that of Flash memories or E²PROM.

FEATURES

Bit configurationSpecial Sector Region	 : 262,144 words × 8 bits : 256 words × 8 bits In this region, data storage after (by) three times reflow based on JEDEC MSL-3 standard condition is guaranteed.
Unique ID	JEDEC MOL-5 standard condition is guaranteed.
Serial Number	: 64 bits In this region, data storage after (by) three times reflow based on
	JEDEC MSL-3 standard condition is guaranteed.
 Serial Peripheral Interface 	: SPI (Serial Peripheral Interfaces)
·	Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)
 Operating frequency 	: 50 MHz (Max)
 High endurance 	: 10 ¹³ times / byte
 Data retention 	: 50.4 years (+85 °C)
	13.7years (+105 °C)
	4.2 years (+125 °C) or more
	Under evaluation for more than 4.2years(+125 °C)
 Operating power supply voltage 	: 1.7 V to 1.95 V
Low power consumption	: Operating power supply current 3.5 mA (Max@50 MHz) Standby current 200 μA (Max)
Operation ambient temperature r	ange : – 40 °C to +125 °C
Package	: 8-pin plastic SOP 150mil
	8-pin plastic DFN 5mm × 6mm
	AEC-Q100 Grade 1 compliant
	RoHS compliant

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PIN ASSIGNMENT

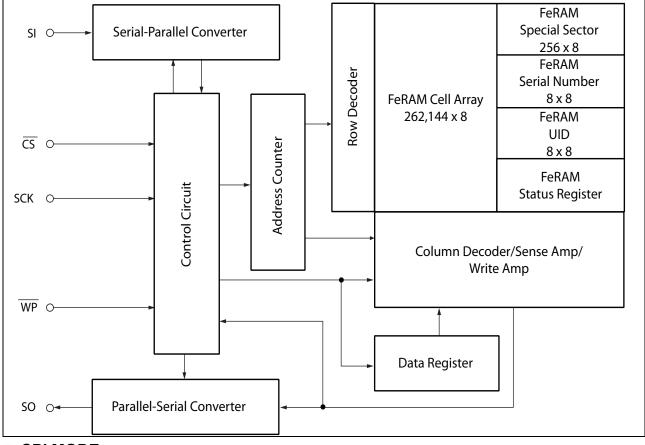


■ PIN FUNCTIONAL DESCRIPTIONS

Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chips select. When \overline{CS} is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When \overline{CS} is "L" level, device is in select (active) status. \overline{CS} has to be "L" level before inputting op-code.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■WRITING PROTECT" for detail.
7	NC	NC pin This pin is not used. No connection or connecting VDD or VCC is allowed.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FeRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin
DIE PAD		It is allowed for the DIE PAD on the bottom of the DFN8 package to be floating (no con- nection to anything) or to be connected to VSS.

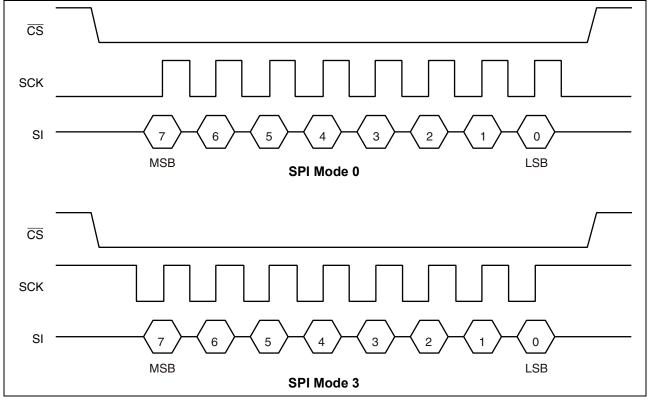
MB85RS2MLY(AEC-Q100 Compliant)

BLOCK DIAGRAM



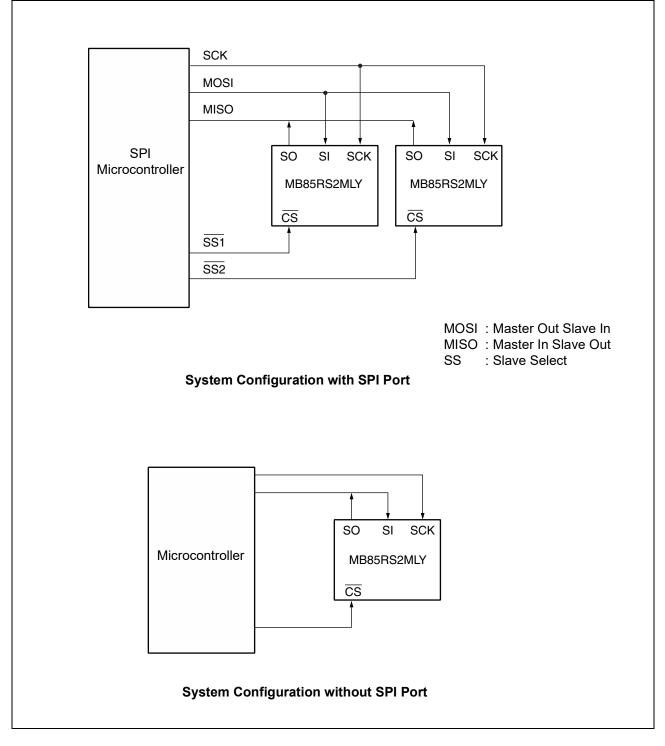
SPI MODE

MB85RS2MLY corresponds to the SPI mode 0 (CPOL = 0, CPHA = 0), and SPI mode 3 (CPOL = 1, CPHA = 1).



SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS2MLY works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



■ STATUS REGISTER

Bit No.	Bit Name	Function			
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FeRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.			
6 to 4		Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.			
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write			
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.			
1	WEL	 Write Enable Latch This indicates FeRAM Array and status register are writable. The WREN command is for setting, and the WRDI command is for resetting. With the RDSR command, reading is possible but writing is not possible with the WRSR command. WEL is reset after the following operations. After power ON. After WRDI command recognition. Achieving continuous writing mode, WEL is not reset after following operations making it possible to execute writing commands continuously. After WRSR command recognition. After WRSN command recognition. After SSWR command recognition. 			
0	0	This is a bit fixed to "0".			

■ OP-CODE

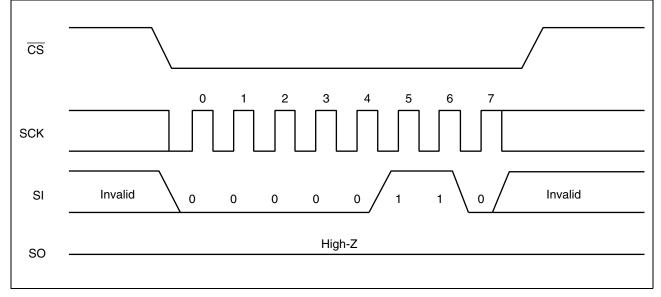
MB85RS2MLY accepts 14 kinds of command specified in op-code. Op-code is a code composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If \overline{CS} is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101 _в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в
FSTRD	Fast Read Memory Code	0000 1011 _в
RDID	Read Device ID	1001 1111в
RUID	Read Unique ID	0100 1100в
WRSN	Write Serial Number	1100 0010в
RDSN	Read Serial Number	1100 0011 _в
SSWR	Write Special Sector	0100 0010в
SSRD	Read Special Sector	0100 1011в
FSSRD	Fast Read Special Sector	0100 1001в
		1011 1001в
		1100 0001в
RFU	Reserved	1100 0110 _B
		1100 1110 _в
		1100 1111в

COMMAND

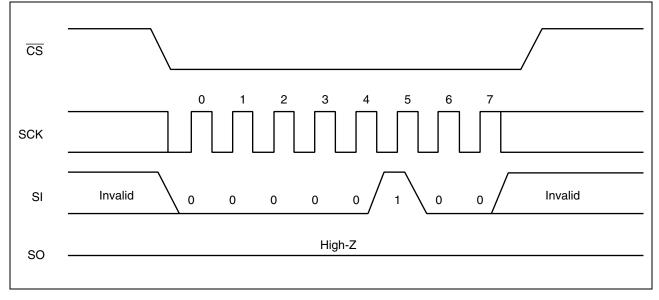
• WREN

The WREN command sets WEL (Write Enable Latch) bit to 1. WEL has to be set with the WREN command before writing operation (WRSR command, WRITE command, WRSN command and SSWR command).



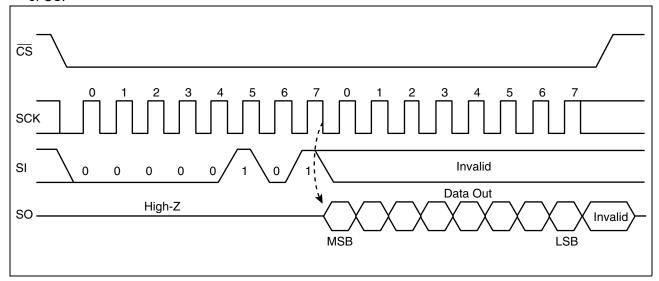
• WRDI

The WRDI command resets WEL (Write Enable Latch) bit to 0. Writing operation (WRSR command, WRITE command, WRSN command and SSWR command) are not performed when WEL is reset.



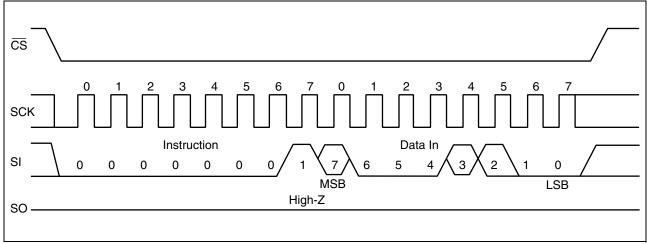
• RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of \overline{CS} .



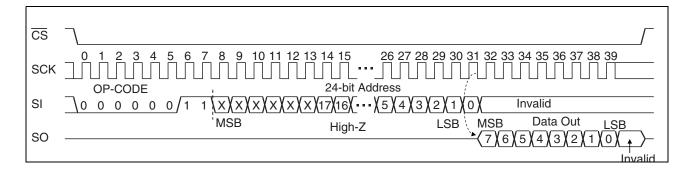
• WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0 of</u> the status register is fixed to "0" and cannot be written. The SI value corresponding to <u>bit 0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the WP signal level until the end of command sequence.



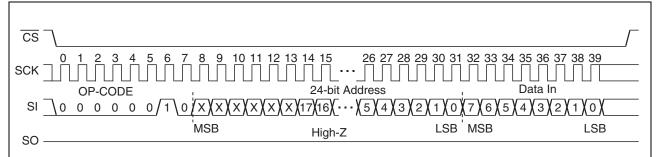
• READ

The READ command reads FeRAM memory cell array data. Arbitrary 24 bits address and op-code of READ are input to SI. The 6-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When \overline{CS} is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before \overline{CS} rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



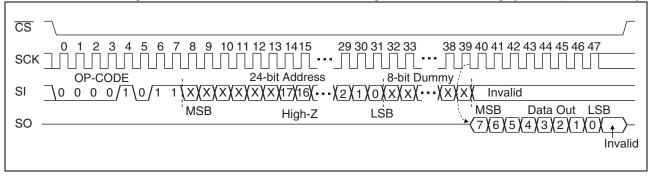
• WRITE

The WRITE command writes data to FeRAM memory cell array. WRITE op-code, arbitrary 24 bits of address and 8 bits of writing data are input to SI. The 6-bit upper address bit is invalid. When 8 bits of writing data is input, data is written to FeRAM memory cell array. Risen \overline{CS} will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before \overline{CS} rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely.



• FSTRD

The FSTRD command reads FeRAM memory cell array data. Arbitrary 24 bits address and op-code of FSTRD are input to SI followed by 8 bits dummy. The 6-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When CS is risen, the FSTRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before CS rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



• RDID

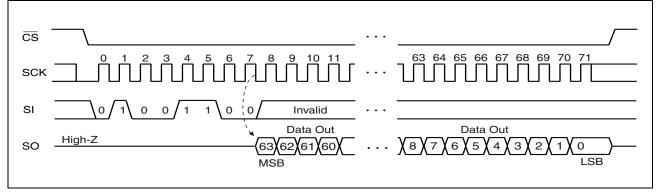
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, 32-bit Device ID is output by continuously sending SCK clock, and SO holds the output state of the last bit until \overline{CS} is risen.

<u>cs</u>										
scк^ 1 2 3 4 5 6 7 8 9 10 11 31 32 33 34 35 36 37 38 39										
SI1 0 0	1 1	1 1	1	In	valid					
SO High-Z	so $\xrightarrow{\text{High-Z}}$ $\xrightarrow{\text{LSB}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{Data Out}}$ $\xrightarrow{\text{LSB}}$									
				b	it					_
	7	6	5	4	3	2	1	0	Hex	
Manufacturer ID	0	0	0	0	0	1	0	0		Fujitsu
Continuation code	0	1	1	1	1	1	1	1	7 Fн	
	Prop	rietar	y use			Densit	у		Hex	
Product ID (1st Byte)	0	1	0	0	1	0	0	0	48 н	Density: 01000 _B = 2Mbit
										·
		Proprietary use Hex								
Product ID (2nd Byte)	0	0	0	0	1	1	0	1	0Dн	

• RUID

The RUID command reads an unique ID which is defined in 64bits for each device. After performing RUID op-code to SI, 64-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK.

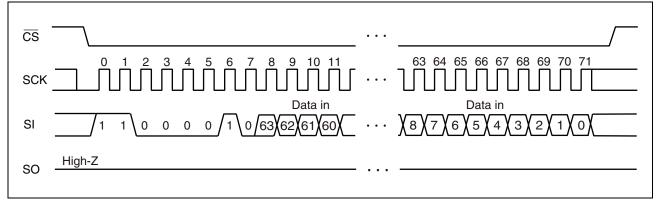
The unique ID is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



•WRSN

The WRSN command writes data to serial number region which is allowed to write only one time. After performing WRSN op-code to SI, 64bits of writing data is input. Once wrote, the serial number region is protected, disabling to overwrite even when issuing WRSN command.

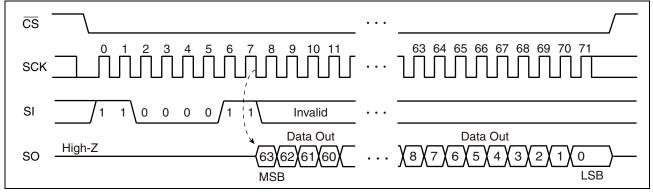
WP signal level shall be fixed before performing WRSN command, and do not change the WP signal level until the end of command sequence.



RDSN

The RDSN command reads 64 bits of serial number which is written using WRSN command. After performing RDSN op-code to SI, 64-cycle clock to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. When reading serial number from devices which no WRSN command is executed, "0" for all bits are output.

The serial number is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



• SSWR

The SSWR command writes data to special sector (a special region of 256 Byte in FeRAM). SSWR op-code, arbitrary 24 bits address and 8-bit writing data are input to SI. The 16-bit upper address is invalid. When input of 8-bit writing data is completed, it starts writing data to special sector. Risen \overline{CS} will terminate the SSWR command, but if you continue the writing data for each before \overline{CS} rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, roll over is not happen, the data hereafter is ignored.

The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.

CS	1			
SCK	0 1 2 3 4 5 6 7 8 9 10 11		.7 28 29 30 31 32 33 34 35 36	37 38 39
	ope. code , 24 b	it addresses	Data	In
SI	$\frac{1}{0} \sqrt{1} = \frac{0}{0} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} 1$	··· \X\7\6\5\∠	3/2/1/0/7/6/5/4/3	(2)(1)(0)
SO -	MSB	High-Z	LSB MSB	LSB
50				

SSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FeRAM). SSWR opcode and arbitrary 24 bits address are input to SI. The 16-bit upper address is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When CS is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before CS rising. When it reaches the most significant address, roll over is not happen.

The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.

$\overline{\text{CS}}$	
SCK	0 1 2 3 4 5 6 7 8 9 10 11 23 24 25 26 27 28 29 30 31 32 33 34 35 36 37 38 39
SI	$\frac{1}{0} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} \sqrt{1} 1$
SO	MSB High-Z LSB MSB Data Out LSB (7)6(5)4(3)2(1)0(
	Invalid

• FSSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FeRAM). SSWR opcode and arbitrary 24 bits address are input to SI followed by 8 bits dummy. The 16-bit upper address is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When \overline{CS} is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before \overline{CS} rising. When it reaches the most significant address, roll over is not happen.

The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.

CS	
SCK	0 1 2 3 4 5 6 7 8 9 10 11 23 24 25 26 2728 29 30 31 32 33 38 39 40 41 42 43 44 45 46 47 ope. code 24 bit addresses 8 bit dummy
SI	$\frac{1}{0} \sqrt{1} \sqrt{2} \sqrt{1} \sqrt{2} \sqrt{2} \sqrt{2} \sqrt{2} \sqrt{2} \sqrt{2} \sqrt{2} 2$
so	MSB High-Z LSB MSB Data Out LSB
	Invalid

BLOCK PROTECT

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0 Protected Block			
0	0 None			
0	1 30000н to 3FFFFн (upper 1/4)			
1	0 20000н to 3FFFFн (upper 1/2)			
1	1 00000н to 3FFFFн (all)			

WRITING PROTECT

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register	
0	Х	Х	Protected	Protected	Protected	
1	0	Х	Protected	Unprotected	Unprotected	
1	1	0	Protected	Unprotected	Protected	
1	1	1	Protected	Unprotected	Unprotected	

■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rat	Unit	
Parameter		Min	Мах	Unit
Power supply voltage*	Vdd	- 0.5	+ 2.5	V
Input voltage*	VIN	- 0.5	V _{DD} + 0.5	V
Output voltage*	Vout	- 0.5	V _{DD} + 0.5	V
Operation ambient temperature	TA	- 40	+ 125	°C
Storage temperature	Tstg	- 55	+ 150	°C

*: These parameters are based on the condition that Vss is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings. Do not exceed any of these ratings.

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
Farameter	Symbol	Min	Тур	Max	Unit
Power supply voltage ^{*1}	Vdd	1.70	1.80	1.95	V
Operation ambient temperature*2	TA	- 40		+ 125	°C

*1: These parameters are based on the condition that Vss is 0 V.

*2: Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

■ ELECTRICAL CHARACTERISTICS

1. DC Characteristics

(within recommended operating conditions)

Parameter	Symbol	Conditio	n		Value		Unit	
Faranieler	Symbol	Condition		Min	Тур	Max	Jint	
		$\overline{CS} = V_{DD}$	25 °C	—		1		
Input lookago ourront*1	II.J		125 °C	—	_	2	۸	
Input leakage current*1	Iu	WP, SCK, CS , SI,	25 °C	—		1	μA	
		= 0 V to V _{DD}	125 °C	—	_	2		
Output leakage current*2	llual	SO = 0 V to V _{DD}	25 °C	—		1	۸	
	I lo	SO = 0 V to V DD	125 °C	—	_	2	μA	
Operating power supply current* ³	ldd	SCK = 50MHz			2.5	3.5	mA	
Standby current	lsв	$SCK = SI = \overline{CS} = \overline{CS}$	$SCK = SI = \overline{CS} = \overline{WP} = V_{DD}$		2	200	μA	
Input high voltage	VIH	V _{DD} = 1.7 V to 1.95 V		$V_{\text{DD}} \times 0.7$	_	$V_{\text{DD}} + 0.3$	V	
Input low voltage	VIL	V _{DD} = 1.7 V to 1.95 V		- 0.3		$V_{\text{DD}} \times 0.3$	V	
Output high voltage	Vон	Iон = − 2 mA		$V_{\text{DD}}-0.5$		_	V	
Output low voltage	Vol	IoL = 2 m/	4			0.4	V	

*1 : Applicable pin : \overline{CS} , \overline{WP} , SCK, SI

*2 : Applicable pin : SO

*3 : Input voltage magnitude : VDD – 0.2 V or VSS

2. AC Characteristics

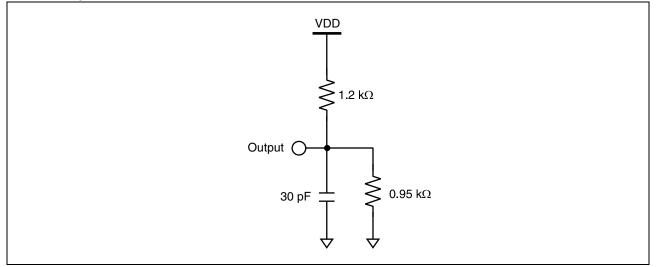
Deremeter	Symbol	Va	lue	Unit	Condition
Parameter	Symbol	Min	Max	Unit	Vdd
SCK clock frequency	fcк		50	MHz	all commands ex- cept for READ/ SSRD
		—	40		READ command
			10		SSRD command
Clock high time	tсн	9		ns	
Clock low time	tc∟	9		ns	
Chip select set up time	t cs∪	5		ns	
Chip select hold time	tсsн	5		ns	
Output disable time	tod		10	ns	
Output data valid time	todv		9	ns	*1
Output hold time	tон	0		ns	
Deselect time	t⊳	40		ns	
Data in rising time	t _R		50	ns	
Data falling time	t⊧		50	ns	
Data set up time	t s∪	5		ns	
Data hold time	t⊦	5		ns	

*1: In SSRD command, 60ns(max.)

AC Test Condition

MB85RS2MLY(AEC-Q100 Compliant)

AC Load Equivalent Circuit



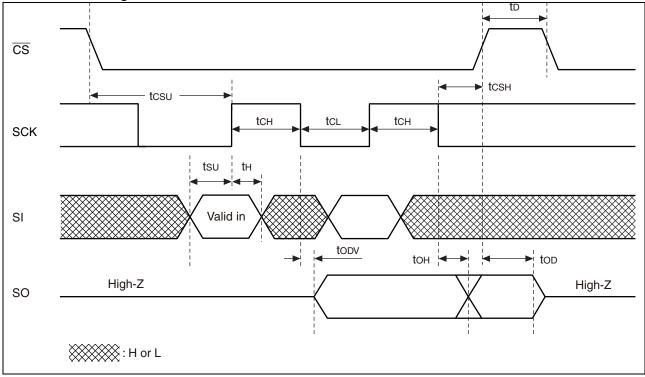
3. Pin Capacitance

Parameter	Symbol	Condition	Va	lue	Unit
Falameter	Symbol	Condition	Min	Max	Onit
Output capacitance	Co	$V_{DD} = 1.8 \text{ V},$ $V_{IN} = V_{OUT} = 0 \text{ V to } V_{DD},$	—	8	pF
Input capacitance	Cı	$f = 1 \text{ MHz}, T_A = +25 \text{ °C}$		6	pF



TIMING DIAGRAM

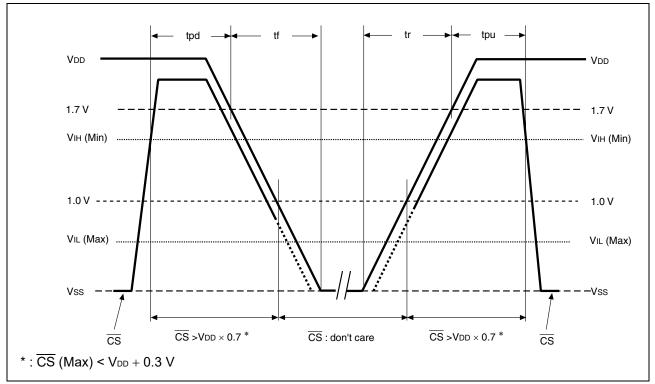
Serial Data Timing





MB85RS2MLY(AEC-Q100 Compliant)

POWER ON/OFF SEQUENCE



Parameter	Symbol	Value		Unit	
	Symbol	Min	Мах	Onic	
CS high level hold time at power OFF	tpd	400		ns	
CS high level hold time at power ON	tpu	450		μs	
Power supply rising time	tr	0.05		ms/V	
Power supply falling time	tf	0.1		ms/V	

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

■ FeRAM CHARACTERISTICS

Parameter	Value		Unit	Remarks	
Farameter	Min	Max		Remarks	
Read/Write Endurance*1	10 ¹³		Times/byte	Operation Ambient Temperature $T_A = + 125 \ ^{\circ}C$	
	4.2 or more*3	—		Operation Ambient Temperature $T_A = + 125 \ ^{\circ}C$	
Data Retention ^{*2}	13.7	—	Years	Operation Ambient Temperature $T_A = +105 \ ^{\circ}C$	
	50.4			Operation Ambient Temperature $T_A = +85 \ ^{\circ}C$	

*1 : Total number of reading and writing defines the minimum value of endurance, as an FeRAM memory operates with destructive readout mechanism.

*2: Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

*3: Under evaluation for more than 4.2years(+125 °C).

NOTE ON USE

We recommend programming of the device after reflow except for special sector region and serial number region. Data written before reflow cannot be guaranteed.

ESD AND LATCH-UP

(8-pin plastic SOP 150mil)

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥ 2000 V
ESD CDM (Charged Device Model) AEC-Q100-011(FI-CDM) compliant	MB85RS2MLYPNF-GS-AWE2 MB85RS2MLYPNF-GS-AWERE2	≥ 1000 V
Latch-Up (I-test) JESD78 compliant		≥ 125mA
Latch-Up (V _{supply} overvoltage test) JESD78 compliant		≥ 2.93V

(8-pin plastic DFN 5mm × 6mm)

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥ 2000 V
ESD CDM (Charged Device Model) AEC-Q100-011(FI-CDM) compliant	MB85RS2MLYPN-GS-AWEWE1	≥ 500 V
Latch-Up (I-test) JESD78 compliant		≥ 125mA
Latch-Up (V _{supply} overvoltage test) JESD78 compliant		≥ 2.93V

REFLOW CONDITIONS AND FLOOR LIFE

[JEDEC MSL] : Moisture Sensitivity Level 3 (ISP/JEDEC J-STD-020E)

Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.



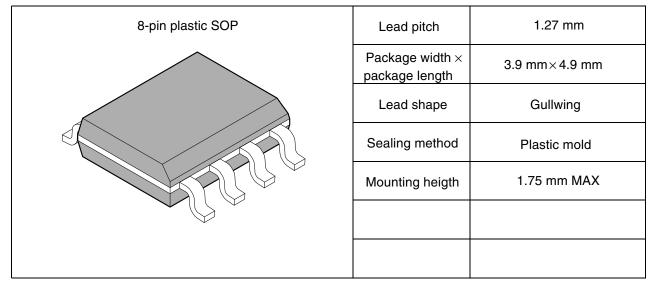
ORDERING INFORMATION

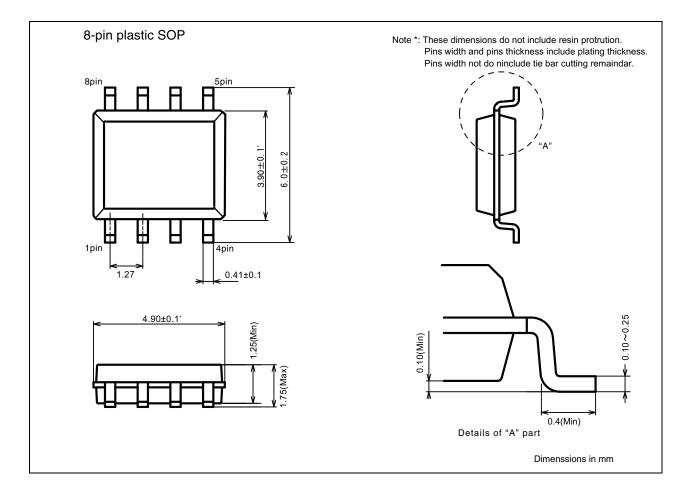
Part number	Package	Shipping form	Minimum shipping quantity
MB85RS2MLYPNF-GS-AWE2	8-pin plastic SOP	Tube	*
MB85RS2MLYPNF-GS-AWERE2	8-pin plastic SOP	Embossed Carrier tape	1500
MB85RS2MLYPN-GS-AWEWE1	8-pin plastic DFN	Embossed Carrier tape	1500

* : Please contact our sales office about minimum shipping quantity.



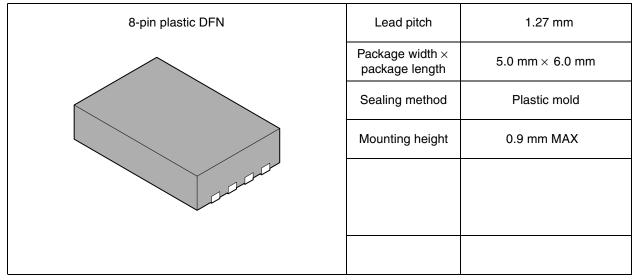
PACKAGE DIMENSION

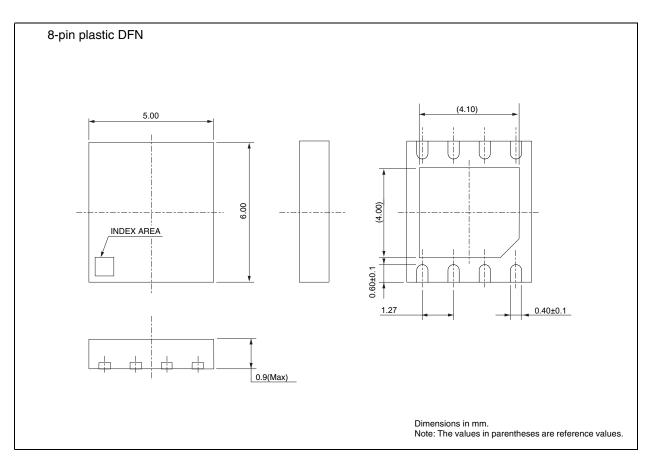




MB85RS2MLY(AEC-Q100 Compliant)

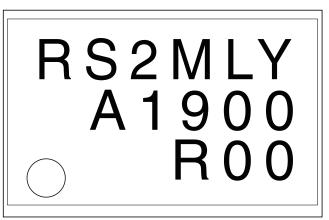
(Continued)





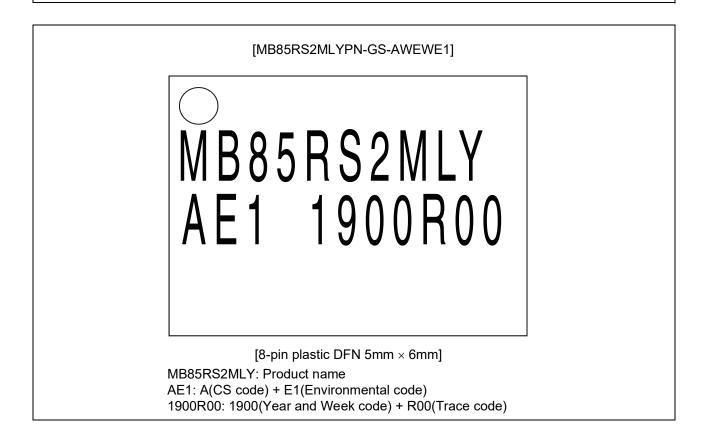
MARKING (Example)

[MB85RS2MLYPNF-GS-AWE2] [MB85RS2MLYPNF-GS-AWERE2]



[8-pin plastic SOP 150mi]

RS2MLY: Product name A1900: A(CS code) + 1900(Year and Week code) R00: Trace code

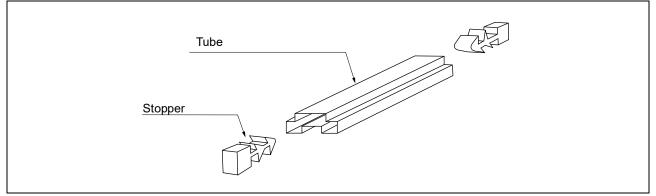


PACKING INFORMATION

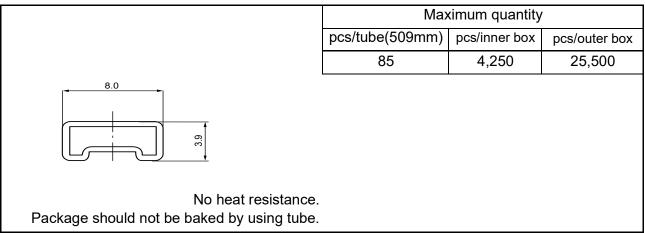
1. Tube

1.1 Tube Dimensions

Tube/stopper shape (example)

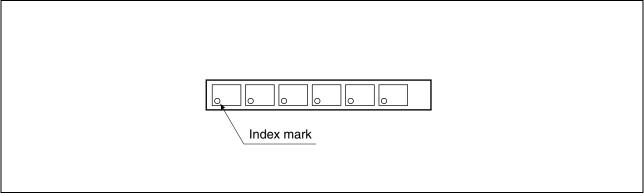


Tube cross-sections and Maximum quantity



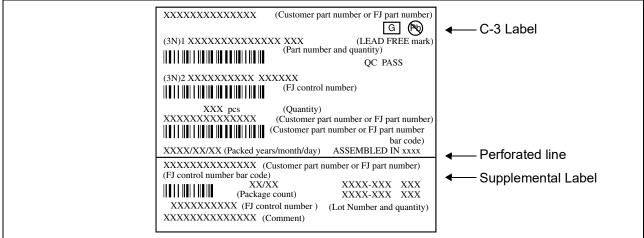
(Dimensions in mm)

Direction of index in tube



1.2 Product label indicators (example)

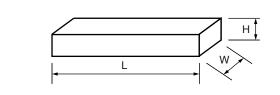
Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]





1.3 Dimensions for Containers

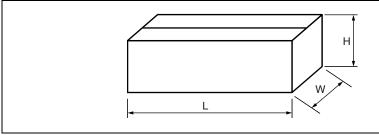
(1) Dimensions for inner box



L	W	Н
549	125	81

(Dimensions in mm)

(2) Dimensions for outer box

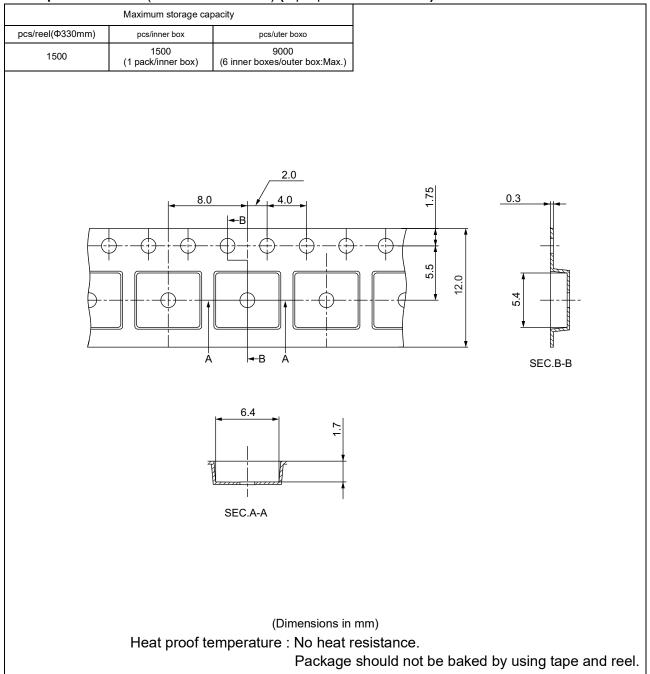


L	W	н
567	272	269

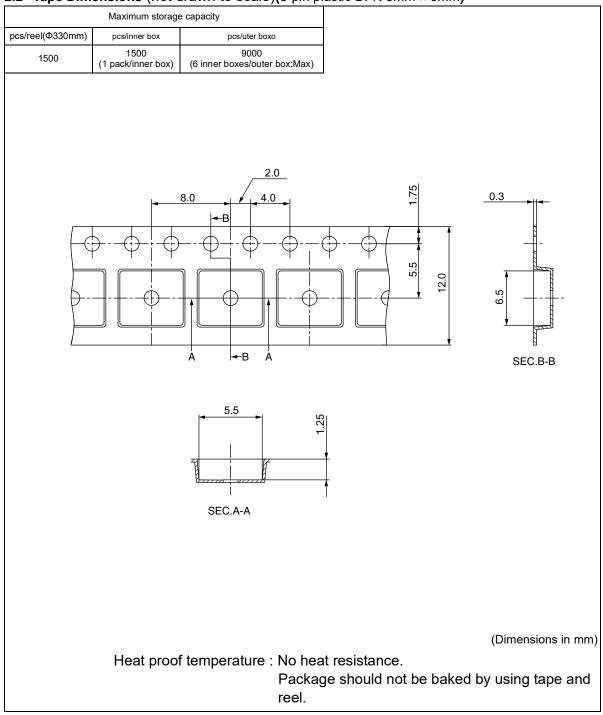
(Dimensions in mm)

2. Emboss Tape

2.1 Tape Dimensions (not drawn to scale) (8-pin plastic SOP 150mil)

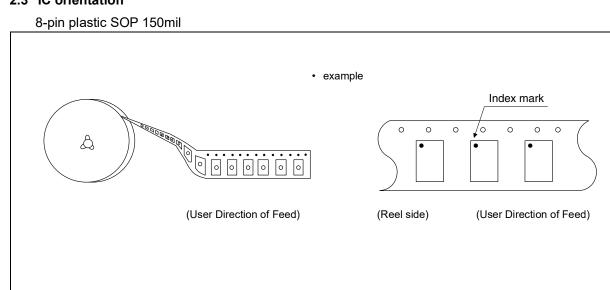




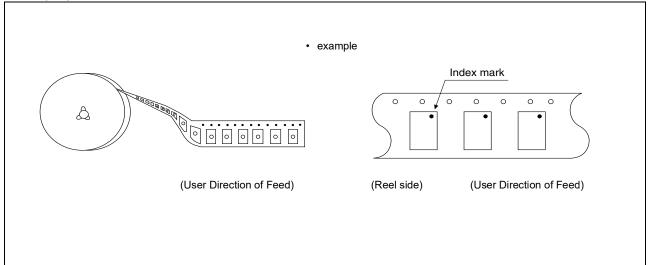


2.2 Tape Dimensions (not drawn to scale)(8-pin plastic DFN 5mm × 6mm)

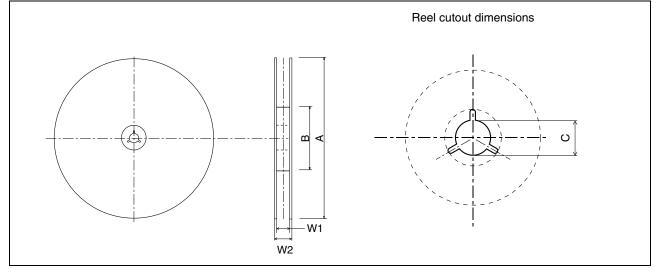
2.3 IC orientation



8-pin plastic DFN 5mm × 6mm



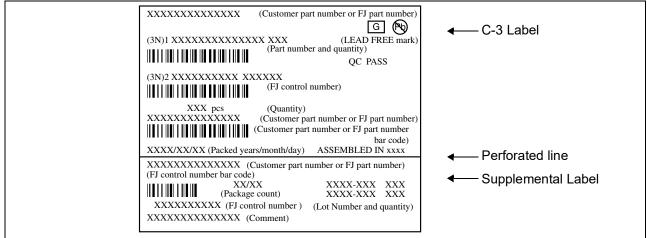
2.4 Reel dimensions



			Dimensio	ons in mm
А	В	С	W1	W2
300	100	13	13.5	17.5

2.5 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

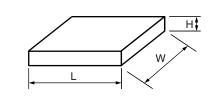


Label II:Moisture Barrier Bag (It sticks it on the Aluminum laminated bag) [MSL Label (100mm × 70mm)]



2.6 Dimensions for Containers

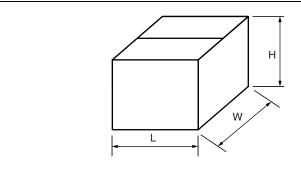
(1) Dimensions for inner box



Tape width	L	W	н
12	350	335	35

(Dimensions in mm)

(2) Dimensions for outer box



L	W	Н
384	368	225

(Dimensions in mm)

■ MAJOR CHANGES IN THIS EDITION

A change on a page is indicated by a vertical line drawn left side of that page.

Page	Section	Change Results
1,20	Data Retention	10 to 50.4 years(+85 °C)
		2.75 to 13.7 years(+105 °C)
		0.85 to 4.2 years(+125 °C)
9	READ command	Numbers of arbitrary address bit.
	WRITE command	16 to 24bits



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Edited: Sales and Marketing Division